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P-Channel 40 V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}$ (Ω) Max.	I _D (A)	Q _g (Typ.)			
- 40	0.012 at V _{GS} = - 10 V	- 15 ^d	33 nC			
- 40	0.016 at V _{GS} = -4.5 V	- 13 ^d	33 110			

SO-8 S 1 S 2 S 3 G 4 Top View

P-Channel MOSFET

FEATURES

• 100% R_g and UIS Tested

APPLICATIONS

- Adaptor Switch
- Load Switch
- Power Management
- Mobile Computing



Parameter		Symbol	Limit	Unit
Drain-Source Voltage	V _{DS}	- 40	V	
Gate-Source Voltage	V _{GS}	± 20	V	
	T _C = 25 °C		- 15 ^d	
Continuous Drain Current (T _{.1} = 150 °C)	T _C = 70 °C		- 12 ^d	
Continuous Diain Current (1) = 130 C)	T _A = 25 °C	l _D	- 11.7 ^{a, b}	
	T _A = 70 °C		- 9.7 ^{a, b}	
Pulsed Drain Current (t = 300 μs)	I _{DM}	- 65	A	
Continuous Source Prais Diade Current	T _C = 25 °C		- 15 ^d	
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	- 2.5 ^{a, b}	
Avalanche Current	L = 0.1 mH	I _{AS}	- 14.5	
Single-Pulse Avalanche Energy	L = 0.1 mn	E _{AS}	18	mJ
	T _C = 25 °C		49	
Maximum Davies Dissination	T _C = 70 °C		31	w
Maximum Power Dissipation	T _A = 25 °C	P _D	3.4 ^{a, b}	VV
	T _A = 70 °C		2.18 ^{a, b}	
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to 150	00	
Soldering Recommendations (Peak Temperature) ^{e, f}		260	— °C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{a, c}	t ≤ 10 s	R _{thJA}	28	35	°C/W	
Maximum Junction-to-Case	Steady State	R _{thJC}	1.9	2.8	- 'C/vv	

Notes:

- a. Surface mounted on 1" x 1" FR4 board.
- b. t = 10 s.
- c. Maximum under steady state conditions is 81 °C/W.
- d. Package limited.



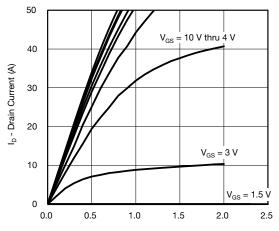
Parameter	Symbol Test Conditions		Min. Typ.		Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V, } I_D = -250 \mu\text{A}$	- 40			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = - 250 μA		- 25		m\//°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$ $I_D = -250 \mu\text{A}$			4.6		mV/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	- 1		- 2.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = -40 V, V _{GS} = 0 V			- 1	μ.Λ	
Zero Gate voltage Diam Current		V _{DS} = - 32 V, V _{GS} = 0 V, T _J = 55 °C			- 5	μA	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge -10 \text{ V}, V_{GS} = -10 \text{ V}$	- 30			Α	
Dunin Course On Chata Basistanasi	В	V _{GS} = - 10 V, I _D = - 10 A		0.012	0.018	018 Ω	
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = - 4.5 V, I _D = - 7 A		0.018	0.026	\$2	
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 10 V, I _D = - 10 A		48		S	
Dynamic ^b							
Input Capacitance	C _{iss}			2982		pF	
Output Capacitance	C _{oss}	$V_{DS} = -20 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		385			
Reverse Transfer Capacitance	C _{rss}			189			
Total Gate Charge	Q _g Q _{gs}	$V_{DS} = -20 \text{ V}, V_{GS} = -10 \text{ V}, I_{D} = -10 \text{ A}$	A	70	115		
Total Gate Charge				33	57	ກດ	
Gate-Source Charge		$V_{DS} = -20 \text{ V}, V_{GS} = -4.5 \text{ V}, I_{D} = -10 \text{ A}$		9.4		- nC -	
Gate-Drain Charge	Q_gd			10.6			
Gate Resistance	R_g	f = 1 MHz	0.4	1.6	3.2	Ω	
Turn-On Delay Time	t _{d(on)}			12			
Rise Time	t _r	V_{DD} = - 20 V, R_L = 1.5 Ω		12			
Turn-Off DelayTime	t _{d(off)}	$I_D \cong$ - 10 A, V_{GEN} = - 10 V, R_g = 1 Ω		49		ns	
Fall Time	t _f			11			
Turn-On Delay Time	t _{d(on)}			62		113	
Rise Time	t _r	V_{DD} = - 20 V, R_L = 1.5 Ω		85			
Turn-Off DelayTime	t _{d(off)}	$I_D \cong -10 \text{ A}, V_{GEN} = -4.5 \text{ V}, R_g = 1 \Omega$		41			
Fall Time	t _f			15			
Drain-Source Body Diode Characterist	ics						
Continous Source-Drain Diode Current	I _S	T _C = 25 °C			- 15	Α	
Pulse Diode Forward Current	I _{SM}				- 65	^	
Body Diode Voltage	V_{SD}	I _S = - 3 A, V _{GS} = 0 V		- 0.7	- 1.2	V	
Body Diode Reverse Recovery Time				23		ns	
Body Diode Reverse Recovery Charge	Q _{rr}	I _F = -10 A, dl/dt = 100 A/μs, T _{.l} = 25 °C		10		nC	
Reverse Recovery Fall Time	t _a	1 _F = -10 Λ, αι/αι = 100 Λ/μ5, 1 _J = 25 °C		9		ns	
Reverse Recovery Rise Time	t _b			15			

a. Pulse test; pulse width \leq 300 µs, duty cycle \leq 2 %. b. Guaranteed by design, not subject to production testing.



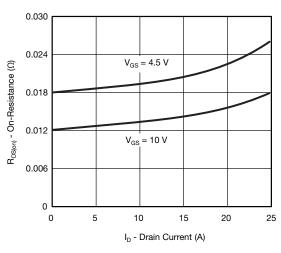


TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

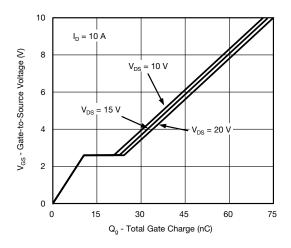


V_{DS} - Drain-to-Source Voltage (V)

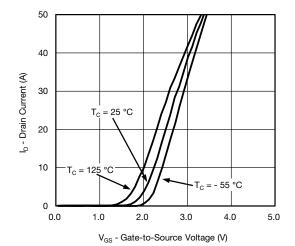
Output Characteristics



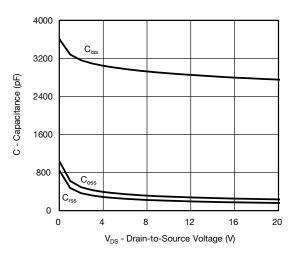
On-Resistance vs. Drain Current



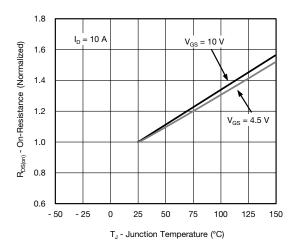
Gate Charge



Transfer Characteristics



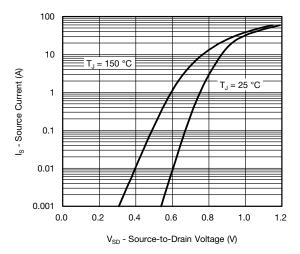
Capacitance



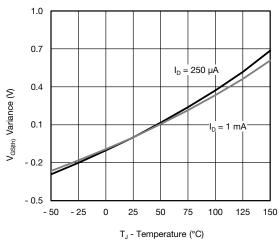
On-Resistance vs. Junction Temperature



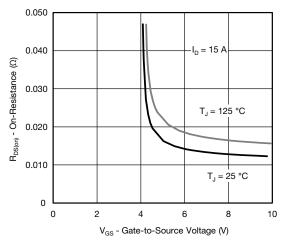
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



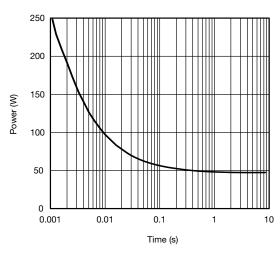
Source-Drain Diode Forward Voltage



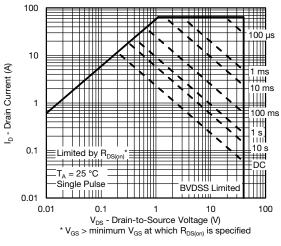
Threshold Voltage



On-Resistance vs. Gate-to-Source Voltage



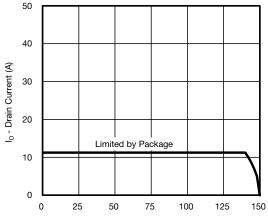
Single Pulse Power, Junction-to-Ambient



Safe Operating Area

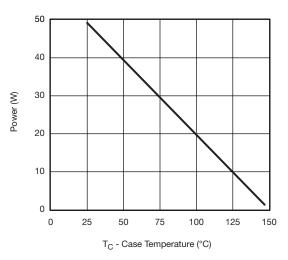
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MOSFET TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

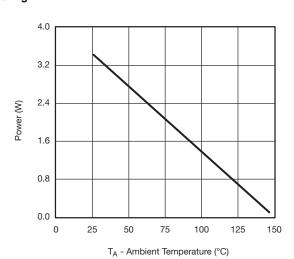


T_C - Case Temperature (°C)

Current Derating*



Power, Junction-to-Case

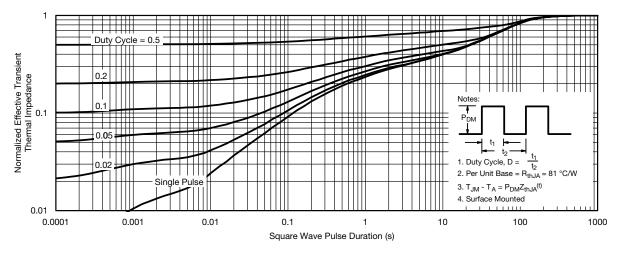


Power, Junction-to-Ambient

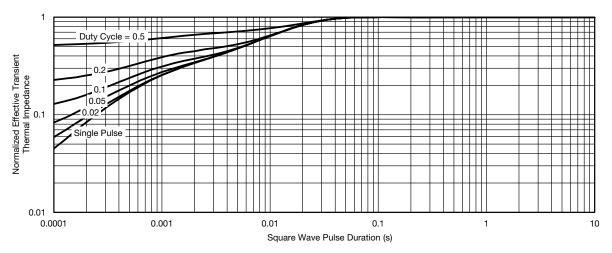
^{*} The power dissipation P_D is based on $T_{J(max.)}$ = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



Normalized Thermal Transient Impedance, Junction-to-Ambient



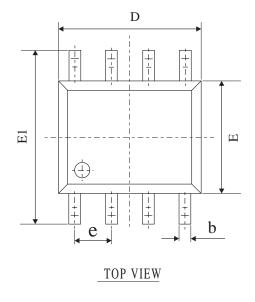
Normalized Thermal Transient Impedance, Junction-to-Case

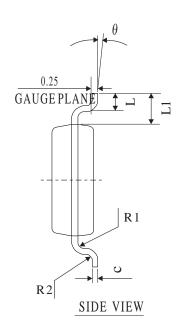


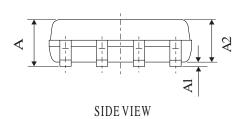
Din-Tek SEMICONDUCTOR

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COMMON DIMENSIONS (UNITS OF MEASURE=MILLIMETER)

SYMBOL	MIN	TYP	MAX	
A	1.30	1.60	1.85	
A1	0.03	0.15	0.28	
A2	1.20	1.45	1.70	
b	0.26	0.40	0.54	
С	0.132	0.203	0.273	
D	4.50	4.90	5.30	
Е	3.50	3.00	4.30	
E1	5.50	6.00	6.50	
L	0.30	0.70	1.10	
θ	2°	4°	6°	
L1	1.04REF			
e	1.27BSC			
R1	0.07TYP			
R2	0.07TYP			





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